Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/766,710	LEE, HEON	
Examiner	Art Unit	
Kin-Chan Chen	1765	

SEARCHED						
Class	Subclass	Date	Examiner			
438 1	700	3/14/2006	ксс			
	702					
	703					
	706					
438	714					
216	8					
216	72					
430	320					
430	323	3/14/06	kic			
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
438	700	1/16/06	k CC			
11	702	1.	1			
	703					
	706					
438	714					
216	72		1			
430	320	'	J			
430	3 > 3	3/16/06	kic			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East Kywords search USPAT, USP4. Pub.  Epo, Jpo, Derwent.  IBM. TDB.  inventor search	3/14/2006	ксс		